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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Group Art Unit: Unassigned  
Examiner: Unassigned

In Re PATENT APPLICATION Of:

Applicant(s) :	Junichi HIKITA et al.	)
Serial No. :	Divisional of Appl. Serial No. 09/499,384	)
Filed :	March 11, 2004	)
For :	SEMICONDUCTOR CHIP AND PRODUCTION THEREOF, AND SEMICONDUCTOR DEVICE HAVING SEMICONDUCTOR CHIP BONDED TO SOLID DEVICE	)
Attorney Ref. :	AI 257 D1	)

**INFORMATION  
DISCLOSURE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, attached are copies of the Forms PTO-1449 from the parent application, serial number, **09/499,384**, which the Examiner may wish to consult during examination of this Divisional Application thereof.

Respectfully submitted,

  
Steven M. Rabin (Reg. No. 29.102)  
RABIN & BERDO, PC  
Customer No. 23995  
Telephone: 202-371-8976  
Facsimile: 202-408-0924

March 11, 2004  
Date

SMR:tl

FEE ENCLOSED:\$ *Ø*  
Please charge any further  
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No. 18-0002

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. ROH-006	SERIAL NO. 09/499,384
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT HIKITA et al.	FILING DATE 02/07/00	GROUP 2811

*O I P E*  
FEB 27 2002

## U.S. PATENT DOCUMENTS

EXAMINER PATENT MARK	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO PART.
<i>u</i>	AG	2-267942	02/94	JAPAN	-	-	ABS <i>*</i>
<i>u</i>	AH	6-37143	11/90	JAPAN	-	-	X <i>*</i>
<i>u</i>	AI	UM 4-99537	08/92	JAPAN	-	-	X <i>*</i>
<i>u</i>	AJ	1-237148	09/89	JAPAN	-	-	ABS <i>*</i>
	AK						
	AL						

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AM	
AN	
AO	

EXAMINER <i>HUNG K. VU</i>	DATE CONSIDERED <i>07/08/02</i>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**Notice of References Cited**

Application/Control No.

09/499,384

Applicant(s)/Patent Under

Reexamination

HIKITA ET AL.

Examiner

Hung K. Vu

Art Unit

2811

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-	US-5,269,453	12-1993	Melton et al.	228/180.22
B	US-				
C	US-				
D	US-				
E	US-				
F	US-				
G	US-				
H	US-				
I	US-				
J	US-				
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<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination HIKITA ET AL.	
			Examiner Hung K. Vu	Art Unit 2811	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	A	US-6,022,792	02-2000	ISHII ET AL.	438	
	B	US-				
	C	US-				
	D	US-				
	E	US-				
	F	US-				
	G	US-				
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	J	US-				
	K	US-				
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